

Dispositivos de semiconductores. Métodos de ensayo mecánicos y climáticos. Parte 18: Radiación ionizante (dosis total) (Ratificada por la Asociación Española de Normalización en julio de 2019.)

UNE-EN IEC 60749-18:2019

Dispositivos de semiconductores. Métodos de ensayo mecánicos y climáticos. Parte 18: Radiación ionizante (dosis total) (Ratificada por la Asociación Española de Normalización en julio de 2019.)

Semiconductor devices - Mechanical and climatic test methods - Part 18: Ionizing radiation (total dose) (Endorsed by Asociación Española de Normalización in July of 2019.)

Dispositifs à semiconducteurs - Méthodes d'essais mécaniques et climatiques - Partie 18: Rayonnements ionisants (dose totale) (Entérinée par l'Asociación Española de Normalización en juillet 2019.)

En cumplimiento del punto 11.2.5.4 de las Reglas Internas de CEN/CENELEC Parte 2, se ha otorgado el rango de documento normativo español UNE al documento normativo europeo EN IEC 60749-18:2019 (Fecha de disponibilidad 2019-05-31)

Este documento está disponible en los idiomas oficiales de CEN/CENELEC/ETSI.

Este anuncio causará efecto a partir del primer día del mes siguiente al de su publicación en la revista UNE.

La correspondiente versión oficial de este documento se encuentra disponible en la Asociación Española de Normalización (Génova 6 28004 MADRID, www.une.org).

Las observaciones a este documento han de dirigirse a:

Asociación Española de Normalización

Génova, 6
28004 MADRID-España
Tel.: 915 294 900
info@une.org
www.une.org

© UNE 2019

Prohibida la reproducción sin el consentimiento de UNE.

Todos los derechos de propiedad intelectual de la presente norma son titularidad de UNE.

This is a preview. [Click here to purchase the full publication.](#)

EUROPEAN STANDARD

EN IEC 60749-18

NORME EUROPÉENNE

EUROPÄISCHE NORM

May 2019

ICS 31.080.01

Supersedes EN 60749-18:2003

English Version

**Semiconductor devices - Mechanical and climatic test methods -
Part 18: Ionizing radiation (total dose)
(IEC 60749-18:2019)**

Dispositifs à semiconducteurs - Méthodes d'essais
mécaniques et climatiques - Partie 18: Rayonnements
ionisants (dose totale)
(IEC 60749-18:2019)

Halbleiterbauelemente - Mechanische und klimatische
Prüfverfahren - Teil 18: Ionisierende Strahlung
(Gesamtdosis)
(IEC 60749-18:2019)

This European Standard was approved by CENELEC on 2019-05-15. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Serbia, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.



European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

The text of document 47/2539/FDIS, future edition 2 of IEC 60749-18, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN IEC 60749-18:2019.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2020-02-15
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2022-05-15

This document supersedes EN 60749-18:2003.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 60749-18:2019 was approved by CENELEC as a European Standard without any modification.